

# Thyristor Diode Modules

## AMKH 460



$V_{RSM}$ V	$V_{RRM}, V_{DRM}$ V	$I_{TRMS} = 800$ A (maximum value for continuous operation) $I_{TAV} = 460$ A (sin 180; $T_C = 85$ °C)	
1700 2300	1600 2200	AMKH 460-16E AMKH 460-22E H4	

Symbols and parameters			Values	Units
$I_{TAV}$	Average on-state current	sin. 180; $T_C = 85$ (100)°C	460 (335)	A
$I_{TSM}$	Surge on-state current	$T_{vj} = 25$ °C; 10 ms	18000	A
		$T_{vj} = 130$ °C; 10 ms	15500	A
$I^2t$	$I^2t$ value, rating for fusing	$T_{vj} = 25$ °C; 10 ms	1620000	A <sup>2</sup> s
		$T_{vj} = 130$ °C; 10 ms	1200000	A <sup>2</sup> s
$V_T$	On-state voltage	$T_{vj} = 25$ °C; $I_T = 1400$ A	max. 1.6	V
$V_{T(TO)}$	On-state threshold voltage	$T_{vj} = 130$ °C	max. 0.88	V
$r_T$	On-state slope resistance	$T_{vj} = 130$ °C	max. 0.45	mΩ
$I_{DD}; I_{RD}$	Forward off-state current; Direct reverse current	$T_{vj} = 130$ °C, $V_{RD} = V_{RRM}$ ; $V_{DD} = V_{DRM}$	max. 240	mA
$t_{gd}$	Gate controlled turn-on delay time	$T_{vj} = 25$ °C; $I_G = 1$ A; $di_G/dt = 1$ A/μs	1	μs
$t_{gr}$	Gate controlled rise time	$V_D = 0.67 \cdot V_{DRM}$	2	μs
$(di/dt)_{cr}$	Critical rate of rise of on-state current	$T_{vj} = 130$ °C	max. 250	A/μs
$(dv/dt)_{cr}$	Critical rate of rise of off-state voltage	$T_{vj} = 130$ °C	max. 1000	V/μs
$t_q$	Turn-off time	$T_{vj} = 130$ °C	100 ... 200	μs
$I_H$	Holding current	$T_{vj} = 25$ °C; typ. / max	150 / 500	mA
$I_L$	Latching current	$T_{vj} = 25$ °C; $R_G = 33\Omega$ ; typ. / max	300 / 2000	mA
$V_{GT}$	Gate trigger voltage	$T_{vj} = 25$ °C; d.c.	min. 3	V
$I_{GT}$	Gate trigger current	$T_{vj} = 25$ °C; d.c.	min. 200	mA
$V_{GD}$	Gate non-trigger voltage	$T_{vj} = 130$ °C; d.c.	max. 0.25	V
$I_{GD}$	Gate non-trigger current	$T_{vj} = 130$ °C; d.c.	max. 10	mA
$R_{th(j-c)}$	Thermal resistance, junction to case	cont. DC; per chip / per module	0.072 / 0.035	K/W
		sin.180; per chip / per module	0.074 / 0.037	K/W
		rec.120; per chip / per module	0.078 / 0.039	K/W
$R_{th(c-s)}$	Thermal resistance, junction to heatsink	per chip / per module	0.02 / 0.01	K/W
$T_{vj}$	Virtual junction temperature		-40 ... +130	°C
$T_{stg}$	Storage temperature range		-40 ... +125	°C
$V_{ISOL}$	Insulation test voltage (r.m.s.)	a.c. 50 Hz; r.m.s.; 1s / 1min.	3600 / 3000	V~
		a.c. 50 Hz; r.m.s.; 1s / 1min.for...H4	4800 / 4000	V~
$M_s$	Mounting torque on heatsink	min / max	5 ± 15 %	Nm
$M_t$	Mounting torque for terminals	min / max	12 ± 15 %	Nm
$a$	Maximum allowable acceleration		5*9.81	m/s <sup>2</sup>
$W$	Weight	approx.	1400	g

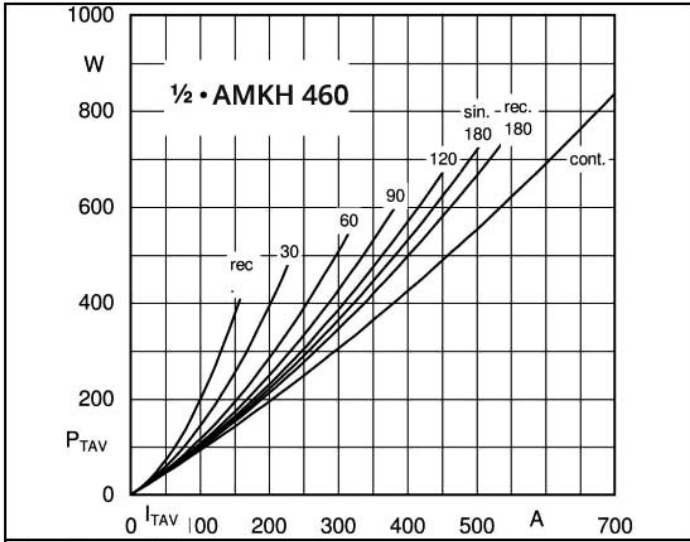


Fig. 1I Power dissipation per thyristor vs. on-state current

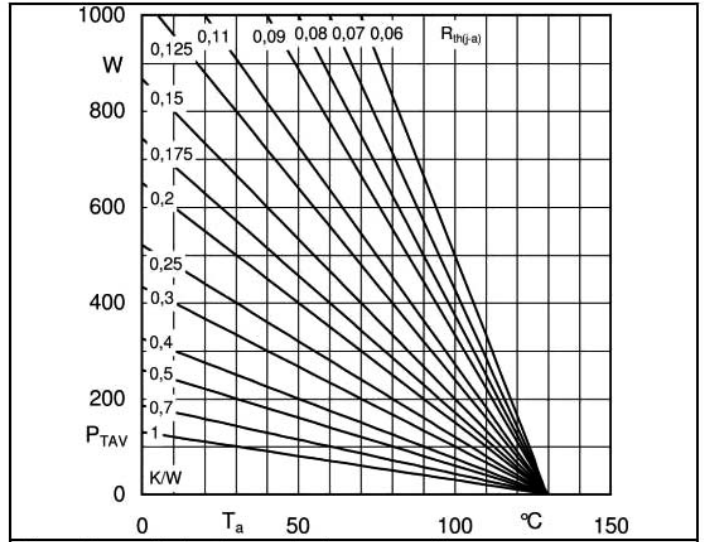


Fig. 1r Power dissipation per thyristor vs. ambient temperature

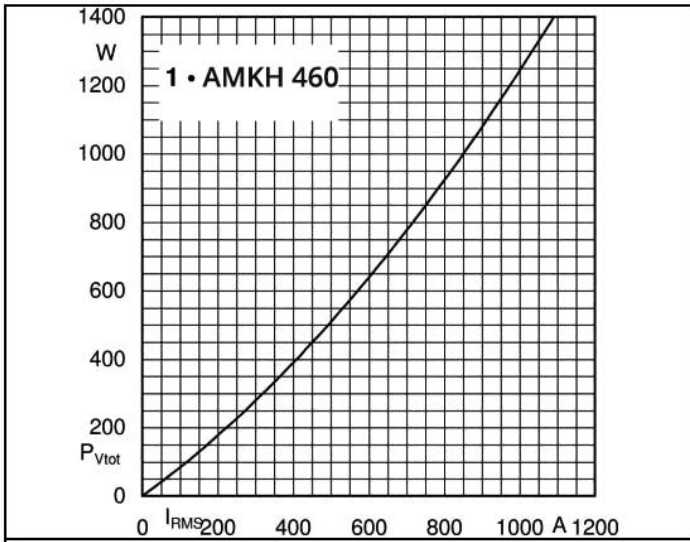


Fig. 2I Power dissipation per module vs. rms current

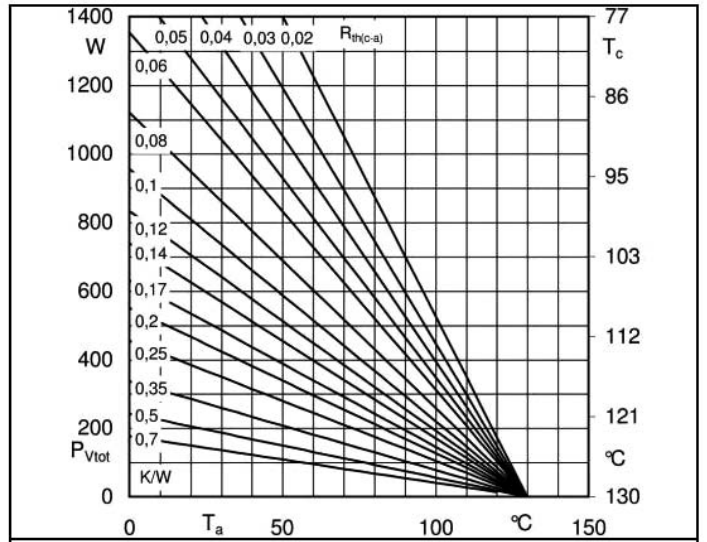


Fig. 2R Power dissipation per modules vs. case temp.

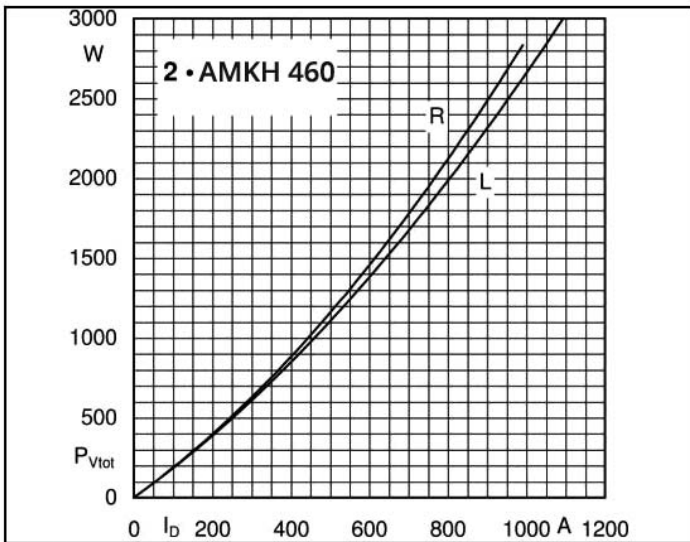


Fig. 3L Power dissipation of two modules vs. direct current

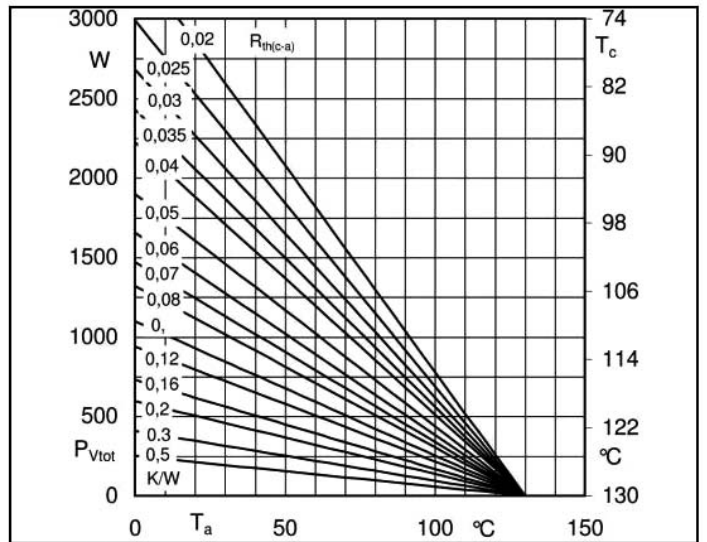


Fig. 3R Power dissipation of two modules vs. case temp.

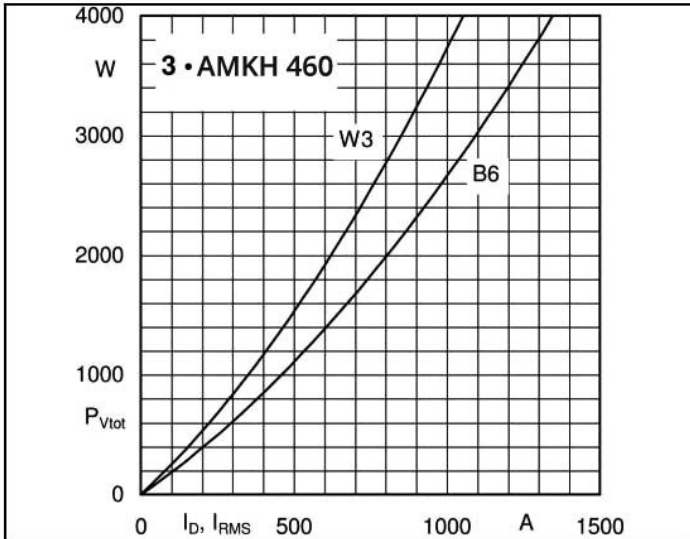


Fig. 4L Power dissipation of three modules vs. direct and rms current

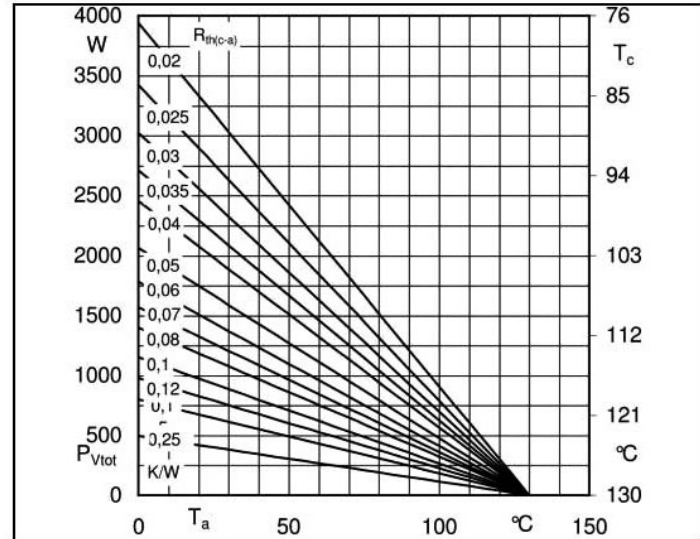


Fig. 4R Power dissipation of three modules vs. case temp.

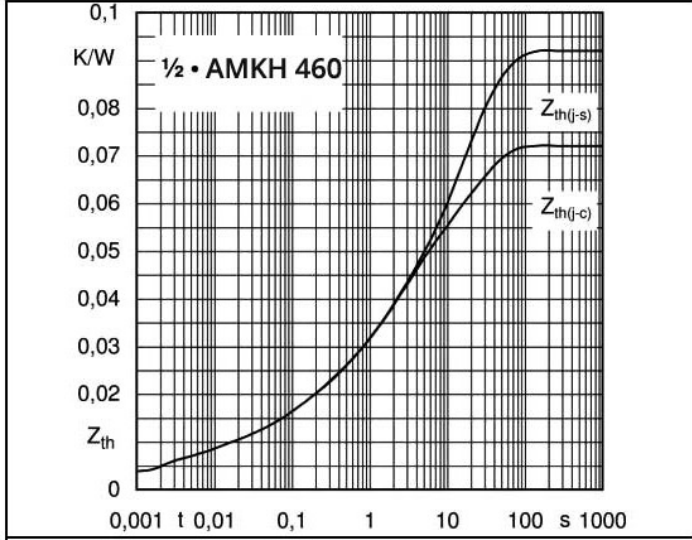


Fig. 6 Transient thermal impedance vs. time

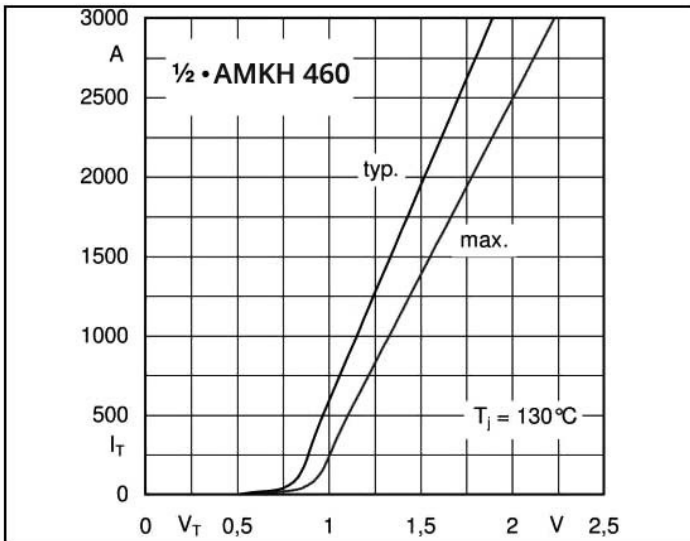


Fig. 7 On-state characteristics

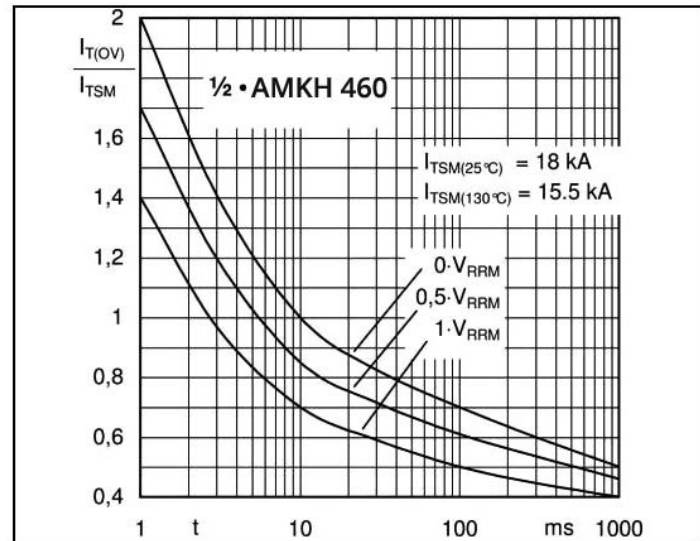
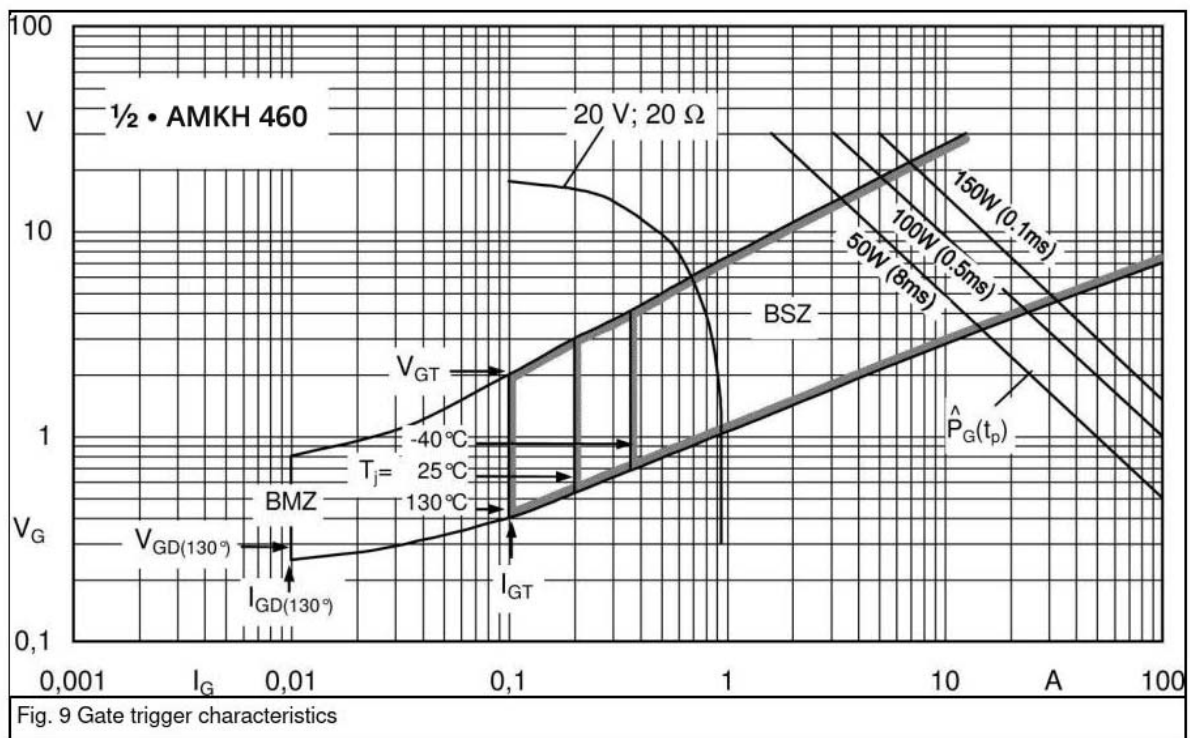
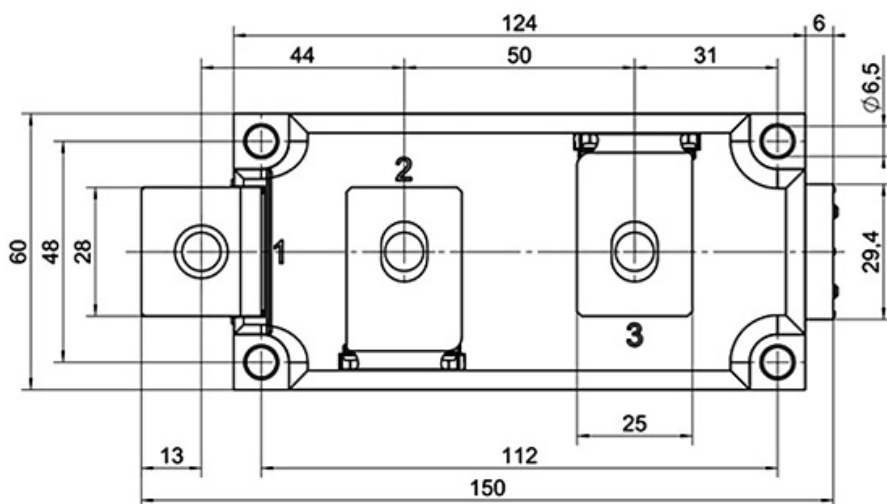
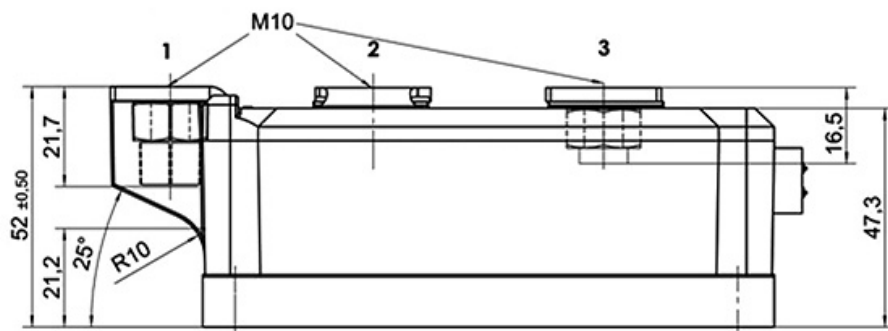
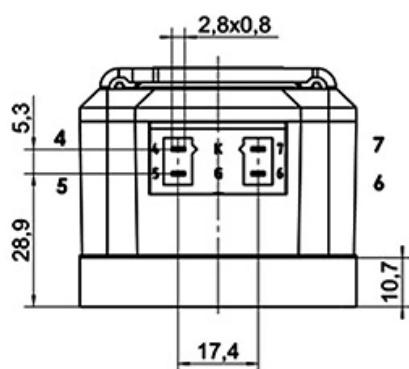


Fig. 8 Surge overload current vs. time





### DIMENSIONS



Dimensions in mm

### TOPOLOGY OF INTERNAL CONNECTION

